# **BUK9E2R4-40C**

## N-channel TrenchMOS logic level FET

Rev. 01 — 11 April 2008

Product data sheet

## 1. Product profile

#### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

#### 1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources
- Q101 compliant
- Suitable for thermally demanding environments due to 175 °C rating

### 1.3 Applications

- 12 V loads
- General purpose power switching
- Automotive systems
- Motors, lamps and solenoids

#### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \geq 25~^{\circ}C;~T_j \leq 175~^{\circ}C$		-	-	40	V
I <sub>D</sub>	drain current	$V_{GS} = 5 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 1 and 4	[1][2]	-	-	100	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see Figure 2		-	-	333	W
Avalanch	ne ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 100 A; $V_{sup} \le$ 40 V; $R_{GS}$ = 50 $\Omega$ ; $V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	1.2	J
Dynamic	characteristics						
$Q_{GD}$	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 32 \text{ V}; \text{ see } \frac{\text{Figure 14}}{\text{Figure 14}}$		-	73	-	nC
Static ch	aracteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \underline{\text{Figure 12}}, \underline{11}$ and $\underline{13}$		-	2.1	2.4	mΩ

<sup>[1]</sup> Continuous current is limited by package.

<sup>[2]</sup> Refer to document 9397 750 12572 for further information.



## 2. Pinning information

Table 2. Pinning

	9			
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		$G \longrightarrow \overline{A}$
mb	D	mounting base; connected to drain		mbb076 S
			SOT226 (I2-PAK)	

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK9E2R4-40C	I2PAK	plastic single-ended package (I2PAK); low-profile 3-lead TO-220AB	SOT226

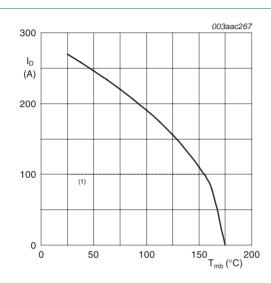
## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 ^{\circ}C;  T_j \le 175 ^{\circ}C$	-	40	V
$V_{DGR}$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	40	V
$V_{GS}$	gate-source voltage		-15	15	V
I <sub>D</sub>	drain current	$T_{mb} = 25 ^{\circ}C; V_{GS} = 5  V; \text{ see } \frac{\text{Figure 1}}{}$	[1] -	270	А
		$V_{GS} = 5 \text{ V}; T_j = 100 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	[2][3]	100	А
		$V_{GS} = 5 \text{ V}; T_j = 25 ^{\circ}\text{C}; \text{ see } \underline{\text{Figure 1}} \text{ and } \underline{4}$	[2][3]	100	А
$I_{DM}$	peak drain current	$T_{mb}$ = 25 °C; $t_p \le 10 \mu s$ ; pulsed; see Figure 4	-	1080	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	333	W
T <sub>stg</sub>	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Avalanci	ne ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D = 100 \text{ A; } V_{sup} \leq 40 \text{ V; } R_{GS} = 50 \Omega;$ $V_{GS} = 5 \text{ V; } T_{j(init)} = 25 \text{ °C; unclamped}$	-	1.2	J
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	see Figure 3	[4][5] <b>-</b> [6]	-	J
Source-	drain diode				
Is	source current	T <sub>mb</sub> = 25 °C	[2][3]	100	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s; \ pulsed; \ T_{mb} = 25 \ ^{\circ}C$	-	1080	Α
BUK9E2R4-40C_	_1			© NXP B.V.	2008. All rights reserv

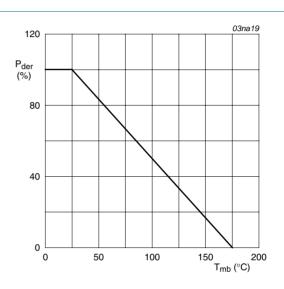
- [1] Current is limited by chip power dissipation rating.
- [2] Continuous current is limited by package.
- [3] Refer to document 9397 750 12572 for further information.
- [4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.
- [5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.
- [6] Refer to application note AN10273 for further information.



$$V_{GS} \ge 5 V$$

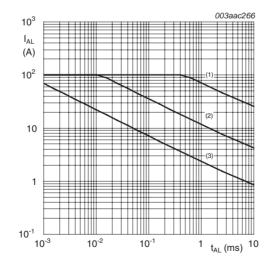
(1) Capped at 100 A due to package.

Fig 1. Continuous drain current as a function of mounting base temperature



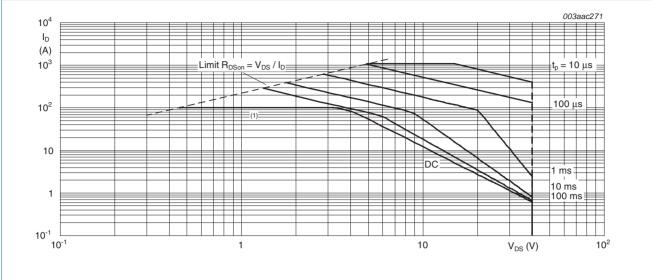
$$P_{der} = \frac{P_{tot}}{P_{tot(25\,^{\circ}C)}} \times 100\,\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



- (1) Single-pulse;  $T_i = 25$  °C.
- (2) Single-pulse;  $T_i = 150 \, ^{\circ}\text{C}$ .
- (3) Repetitive.

Fig 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time



 $T_{mb}$  = 25 °C;  $I_{DM}$  is single pulse

(1) Capped at 100 A due to package.

Fig 4. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

#### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see <u>Figure 5</u>	-	-	0.45	K/W

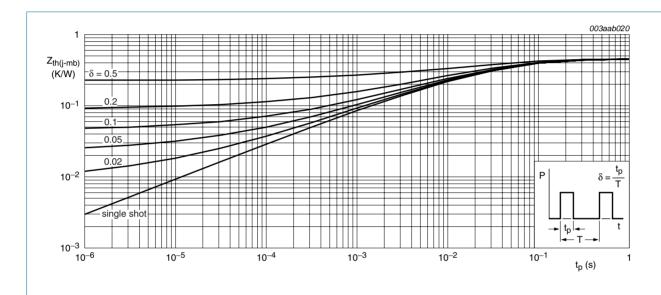


Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

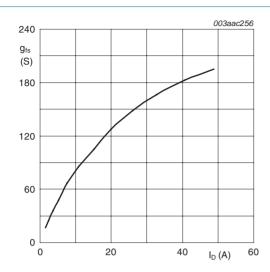
## 6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V;$ $T_j = 25 ^{\circ}C$	40	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V;$ $T_j = -55 \text{ °C}$	36	-	-	V
V <sub>GS(th)</sub> gate-source voltage	_	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see Figure 9 and 10	1	1.5	2	V
		$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = -55 \text{ °C}$ ; see Figure 9	-	-	2.3	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 175$ °C; see Figure 9	0.5	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V};$ $T_j = 175 ^{\circ}\text{C}$	-	-	500	μА
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.02	1	μΑ
BUK9E2R4-40C_1					© NXP B.V. 20	008. All rights reserv

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I <sub>GSS</sub>	gate leakage current	$V_{DS}$ = 0 V; $V_{GS}$ = 15 V; $T_j$ = 25 °C	-	2	100	nΑ
		$V_{DS} = 0 \text{ V}; V_{GS} = -15 \text{ V};$ $T_j = 25 \text{ °C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	-	2.7	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	1.8	2.1	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 11	-	-	4.6	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 12, 11 and 13	-	2.1	2.4	$m\Omega$
Source-dra	ain diode					
$V_{SD}$	source-drain voltage $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 16		-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 25 \text{ A}; dI_S/dt = 100 \text{ A/}\mu\text{s};$	-	70	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 30 \text{ V}$	-	60	-	nC
Dynamic o	haracteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$	-	120	-	nC
$Q_{GS}$	gate-source charge	see Figure 14	-	30	-	nC
$Q_{GD}$	gate-drain charge		-	73	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V};$	-	12487	16700	pF
Coss	output capacitance	f = 1 MHz; T <sub>j</sub> = 25 °C; see Figure 15	-	1323	1600	pF
C <sub>rss</sub>	reverse transfer capacitance	- see <u>rigure 13</u>	-	938	1290	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega;$	-	130	-	ns
t <sub>r</sub>	rise time	$V_{GS}$ = 5 V; $R_{G(ext)}$ = 10 $\Omega$	-	310	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	380	-	ns
t <sub>f</sub>	fall time		-	250	-	ns
L <sub>D</sub>	internal drain inductance	from drain lead 6 mm from package to centre of die	-	4.5	-	nΗ
L <sub>S</sub>	internal source inductance	from source lead to source bond pad	-	7.5	-	nΗ



$$T_i = 25 \, ^{\circ}C; V_{DS} = 25 \, V$$

Fig 6. Forward transconductance as a function of drain current; typical values

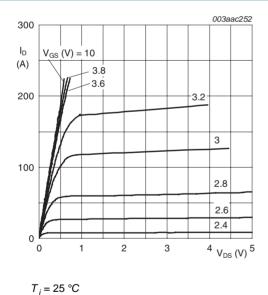
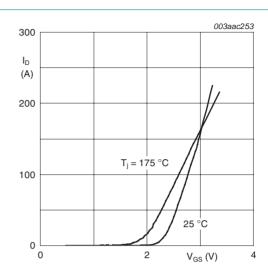
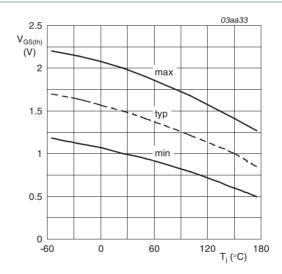


Fig 8. Output characteristics: drain current as a function of drain-source voltage; typical values



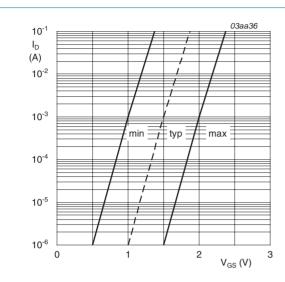
 $V_{DS} = 25 V$ 

Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $I_D = 1 \, mA; V_{DS} = V_{GS}$ 

Fig 9. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25$  °C;  $V_{DS} = V_{GS}$ 

Fig 10. Sub-threshold drain current as a function of gate-source voltage

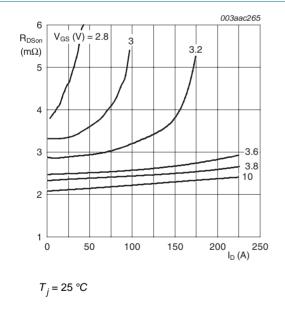
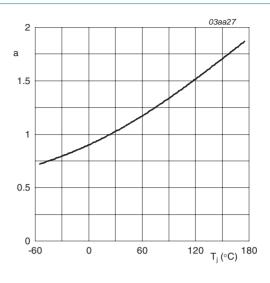
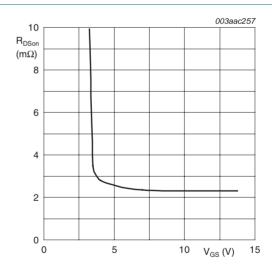


Fig 12. Drain-source on-state resistance as a function of drain current; typical values



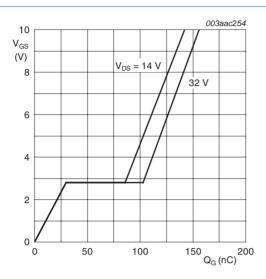
$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 11. Normalized drain-source on-state resistance factor as a function of junction temperature



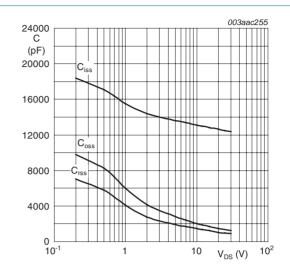
$$T_i = 25 \, ^{\circ}\text{C}; I_D = 25 \, A$$

Fig 13. Drain-source on-state resistance as a function of gate-source voltage; typical values



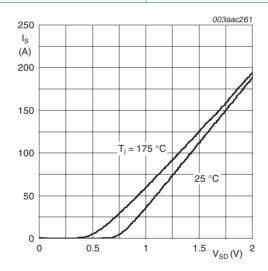
 $T_i = 25 \,^{\circ}C; I_D = 25 \,^{\circ}A$ 

Fig 14. Gate-source voltage as a function of gate charge; typical values



$$V_{GS} = 0 V; f = 1 MHz$$

Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{GS} = 0 V$ 

Fig 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

## 7. Package outline

Plastic single-ended package (I2PAK); low-profile 3-lead TO-220AB

**SOT226** 

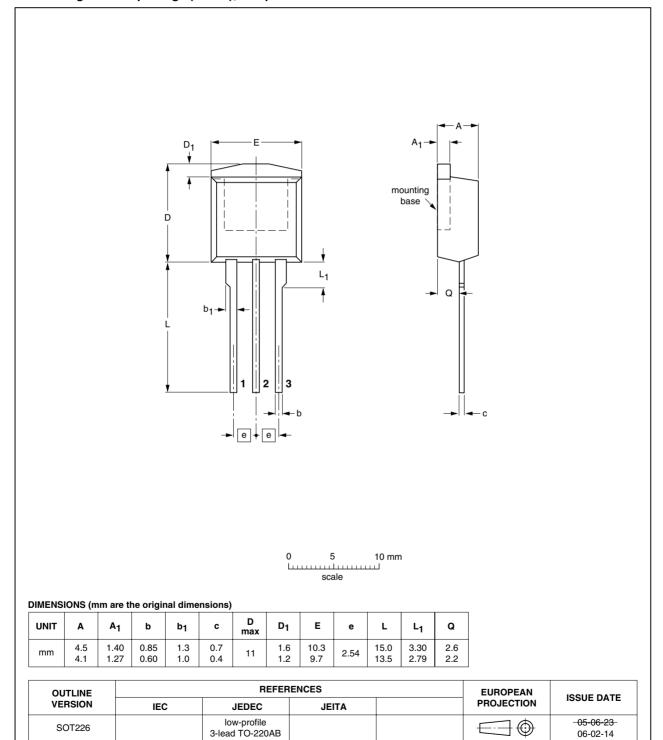


Fig 17. Package outline SOT226 (I2PAK)



## 8. Revision history

#### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9E2R4-40C_1	20080411	Product data sheet	-	-

### 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

#### 9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

#### 9.3 Disclaimers

**General** — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental

damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

**Quick reference data** — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <a href="http://www.nxp.com/profile/terms">http://www.nxp.com/profile/terms</a>, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

**No offer to sell or license** — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

#### 9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

#### 10. Contact information

For additional information, please visit: <a href="http://www.nxp.com">http://www.nxp.com</a>

For sales office addresses, send an email to: salesaddresses@nxp.com

## 11. Contents

1	Product profile
1.1	General description 1
1.2	Features and benefits
1.3	Applications 1
1.4	Quick reference data 1
2	Pinning information 2
3	Ordering information 2
4	Limiting values 2
5	Thermal characteristics 5
6	Characteristics 5
7	Package outline
8	Revision history11
9	Legal information 12
9.1	Data sheet status
9.2	Definitions
9.3	Disclaimers
9.4	Trademarks12
10	Contact information 12
11	Contents 13

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.





